
Key Comparison

Final report on key comparison CCEM-K2 of resistance standards at 10 M Ω and 1 G Ω

R. F. Dziuba and D. G. Jarrett

Abstract. An international comparison of dc resistance at 10 M Ω and 1 G Ω was organized under the auspices of the Consultative Committee for Electricity and Magnetism (CCEM) and piloted by the National Institute of Standards and Technology (NIST, USA). This CCEM comparison began in August 1996 and was completed in March 2000 with the participation of fourteen other national metrology institutes (NMIs). The travelling package included three wirewound 10 M Ω standards and three film-type 1 G Ω standards designed by the NIST. Results indicate that the differences at 10 M Ω and 1 G Ω between each laboratory's values and the respective reference value, are all within each laboratory's expanded relative uncertainty at a coverage factor $k = 2$.

Main text

To reach the main text of this paper, click on [Final Report](#). Note that this text is that which appears in Appendix B of the BIPM key comparison database, www.bipm.org/kcdb.